Search Notes					

Application/Control No.	Applicant(s)/Patent under Reexamination
10/086,602	CHANG ET AL.
Examiner	Art Unit
Steven HD Nauven	2616

SEARCHED					
Class	Subclass	Date	Examiner		
370	352, 466	3/31/2006	ST		
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
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